Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/785,259	OHKAWA ET AL.	
Examiner	Art Unit	
B. Chen	1762	

SEARCHED					
Class	Subclass	Date	Examiner		
updated	previous	2/24/2006	вс		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
east		2/24/2006	вс
	4		